

**Notice of References Cited**Application/Control No.  
09/862,557Applicant(s)/Patent Under  
Reexamination  
KIKUCHI, HIROKIExaminer  
Virginia M KiblerArt Unit  
2623

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,172,373 B1	01-2001	Hara et al.	250/548
	B	US-5,576,831 A	11-1996	Nikoonahad et al.	356/623
	C	US-5,760,408	06-1998	Kikuchi et al.	250/492.2
	D	US-4,725,722	02-1988	Maeda et al.	356/624
	E	US-5,661,548	08-1997	Imai, Yuji	355/55
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Komatsu et al., "A new auto-focus method in critical dimension measurement SEM," IEEE 1997, pages 202-207.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.